Search Notes					

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
09/901,502	KOO ET AL.	
Examiner	Art Unit	
Shick C. Hom	2666	

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Class	Subclass	Date	Examiner
370	216, 227, 228, 229, 237, 320,	7/18/2005	SH
370	335, 337,	7/18/2005	SH
370	342, 537,	7/18/2005	SH
370	538, 540	7/18/2005	SH
455	509, 510	7/18/2005	SH
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INI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

(INCLUDING SE	CH NOTES EARCH STRATEGY	')
	DATE	EXMR
East Search	7/18/2005	SH
Inventor search	7/18/2005	SH
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